

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Jong-Cheol Lee, et al. **ATTY DOCKET NO.** : 8836-223JHM/ID12244US
SERIAL NO. : 10/748,906 **EXAMINER** : Cynthia H. Britt
FILED : December 30, 2003 **ART UNIT** : 2117
TITLE : *SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE*

MAIL STOP: AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

S I R :

In response to the Official Action of December 28, 2007, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the Drawings are set forth on page 2 of this Amendment and include a Replacement Sheet for FIG. 2.

Amendments to the claims are reflected in the Listing of Claims that begins on page 3 of this Amendment.

The Remarks portion begins on page 7 of this Amendment.

Attached to this Amendment is an Exhibit A, in which reference numerals shown in FIG. 3, for example, are inserted by hand.